

**BEST AVAILABLE COPY**Amendments to the Claims

1. (Currently Amended) A method of forming a semiconductor structure comprising a substrate having a patterned Oxide-Nitride-Oxide (ONO) insulating layer over a portion thereof, ~~comprising and characterized by the steps of forming an insulating layer comprising an Oxide-Nitride-Silicon layered structure on the substrate, applying a photoresist to a silicon surface of the Oxide-Nitride-Silicon layered structure as part of a patterning process and stripping the photoresist from the silicon surface of the Oxide-Nitride-Silicon layered structure once a~~ required patterning step has been completed, and subsequently re-oxidizing the silicon layer of the remaining Oxide-Nitride-Silicon structure so as to form an ONO insulating layer structure.
2. (Original) A method as claimed in claim 1, wherein the silicon layer comprises an amorphous silicon layer.
3. (Previously Presented) A method as claimed in claim 1, wherein a non-volatile memory cell is applied as part of the semiconductor structure, which non-volatile memory cell employs the ONO insulating layer between a floating gate and control gate thereof.
4. (Original) A method as claimed in claim 3, wherein the non-volatile memory cell is applied with a control gate formed from a conductive layer which also serves to form part of a peripheral semiconductor structure.

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5. (Previously Presented) A method as claimed in claim 1, wherein the subsequent oxidation of the silicon sub-layer of the Oxide-Nitride-Silicon insulating layer takes place also to provide a high voltage oxide layer for a peripheral structure.

6. (Previously Presented) A method as claimed in claim 1, wherein the silicon layer is re-oxidized into a thermal oxide.

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